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S29VS/XS-R MirrorBit[®] Flash Family

S29VS256R, S29VS128R, S29XS256R, S29XS128R
256/128 Megabit (32/16 Megabyte)
1.8 V Burst 16-bit Data Bus, Simultaneous Read/Write,
Multiplexed MirrorBit Flash Memory

Data Sheet (Advance Information)



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Data Sheet (Advance Information)

Features

- Single 1.8 V supply for read/program/erase (1.70–1.95 V)
- 65 nm MirrorBit Technology
- Address and Data Interface Options
 - Address and Data Multiplexed for reduced I/O count (ADM) S29VS-R
 - Address-High, Address-Low, Data Multiplexed for minimum I/O count (AADM) S29XS-R
- Simultaneous Read/Write operation
- 32-word Write Buffer
- Bank architecture
 - Eight-bank
- Four 32-KB sectors at the top or bottom of memory array 255/127 of 128-KB sectors
- Programmable linear (8/16-word) with wrap around and continuous burst read modes
- Secured Silicon Sector region consisting of 128 words each for factory and customer
- 10-year data retention (typical)
- Cycling Endurance: 100,000 cycles per sector (typical)
- RDY output indicates data available to system
- Command set compatible with JEDEC (42.4) standard
- Hardware sector protection via V_{PP} pin
- Handshaking by monitoring RDY
- Offered Packages
 - 44-ball FBGA (6.2 mm x 7.7 mm x 1.0 mm)
- Low V_{CC} write inhibit
- Write operation status bits indicate program and erase operation completion
- Suspend and Resume commands for Program and Erase operations
- Asynchronous program operation, independent of burst control register settings
- V_{PP} input pin to reduce factory programming time
- Support for Common Flash Interface (CFI)

General Description

The Spansion S29VS256/128R and S29XS256/128R are MirrorBit® Flash products fabricated on 65 nm process technology. These burst mode Flash devices are capable of performing simultaneous read and write operations with zero latency on two separate banks using multiplexed data and address pins. These products can operate up to 108 MHz and use a single V_{CC} of 1.7 V to 1.95 V that makes them ideal for the demanding wireless applications of today that require higher density, better performance, and lowered power consumption. The S29VS256/128R operates in ADM mode, while the S29XS256/128R can operate in the AADM mode.

Performance Characteristics

Read Access Times	
Speed Option (MHz)	108
Max. Synch. Latency, ns (t _A)	72.34
Max. Synch. Burst Access, ns (t _{BACC})	6.75
Max. Asynch. Access Time, ns (t _{ACC})	80
Max OE# Access Time, ns (t _{OE})	15

Current Consumption (typical values)	
Continuous Burst Read @ 108 MHz	32 mA
Simultaneous Operation @ 108 MHz	71 mA
Program/Erase	30 mA
Standby Mode	30 µA

Typical Program & Erase Times	
Single Word Programming	170 µs
Effective Write Buffer Programming (V _{CC}) Per Word	14.1 µs
Effective Write Buffer Programming (V _{PP}) Per Word	9 µs
Sector Erase (16 Kword Sector)	350 ms
Sector Erase (64 Kword Sector)	800 ms

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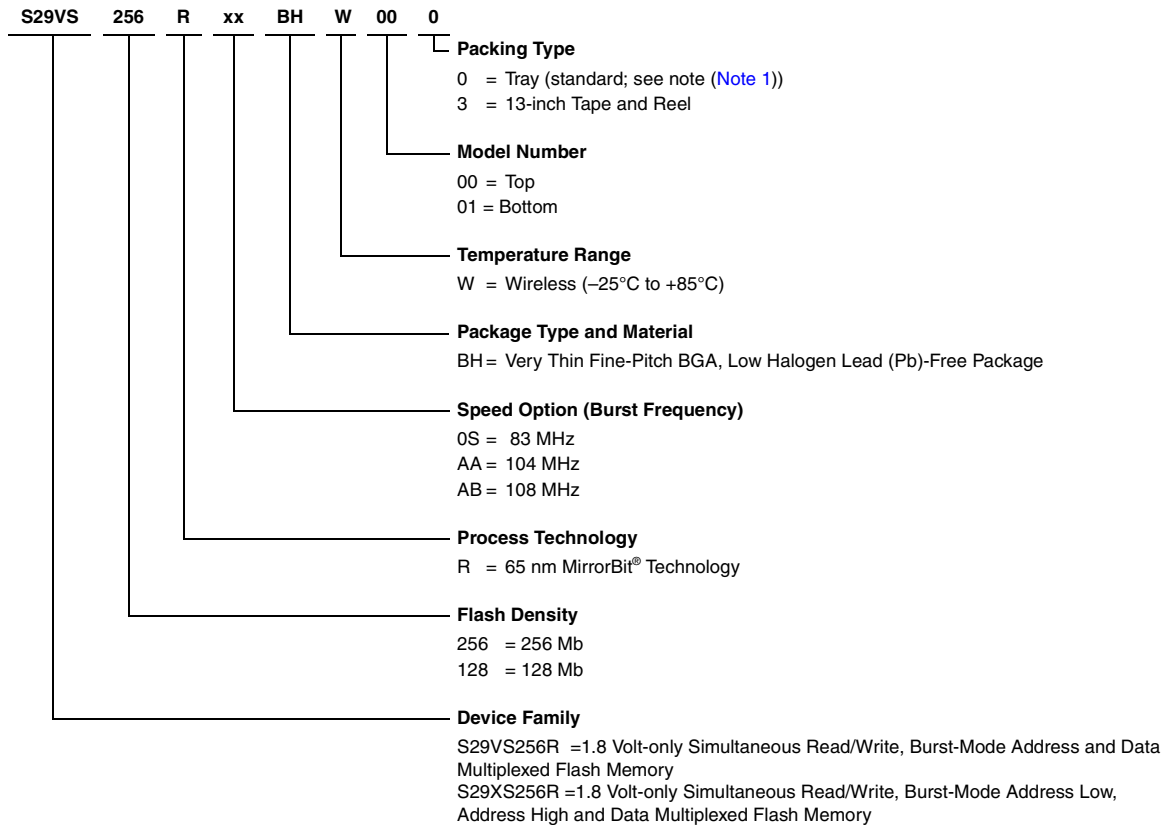
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1. Ordering Information

The ordering part number is formed by a valid combination of the following:



1.1 Valid Combinations

Valid Combination list configurations are planned to be supported in volume for this device. Consult your local sales office to confirm availability of specific valid combinations and to check on newly released combinations.

S29VS-R Valid Combinations (1) (2)				Model Numbers	Package Type (2)
Base Ordering Part Number	Speed Option	Package Type, Material, and Temperature Range	Packing Type		
S29VS256R	0S, AA, AB	BHW (3)	0, 3 (1)	00, 01	6.2 mm x 7.7 mm, 44-ball
S29VS128R					
S29XS256R					
S29XS128R					

Notes:

1. Type 0 is standard. Specify other options as required.
2. BGA package marking omits leading S29 and packing type designator from ordering part number.
3. Industrial Temperature Range is also available. For device specification differences, please refer to the Specification Supplement with Publication Number S29VS_XS-R_SP.

2. Input/Output Descriptions & Logic Symbol

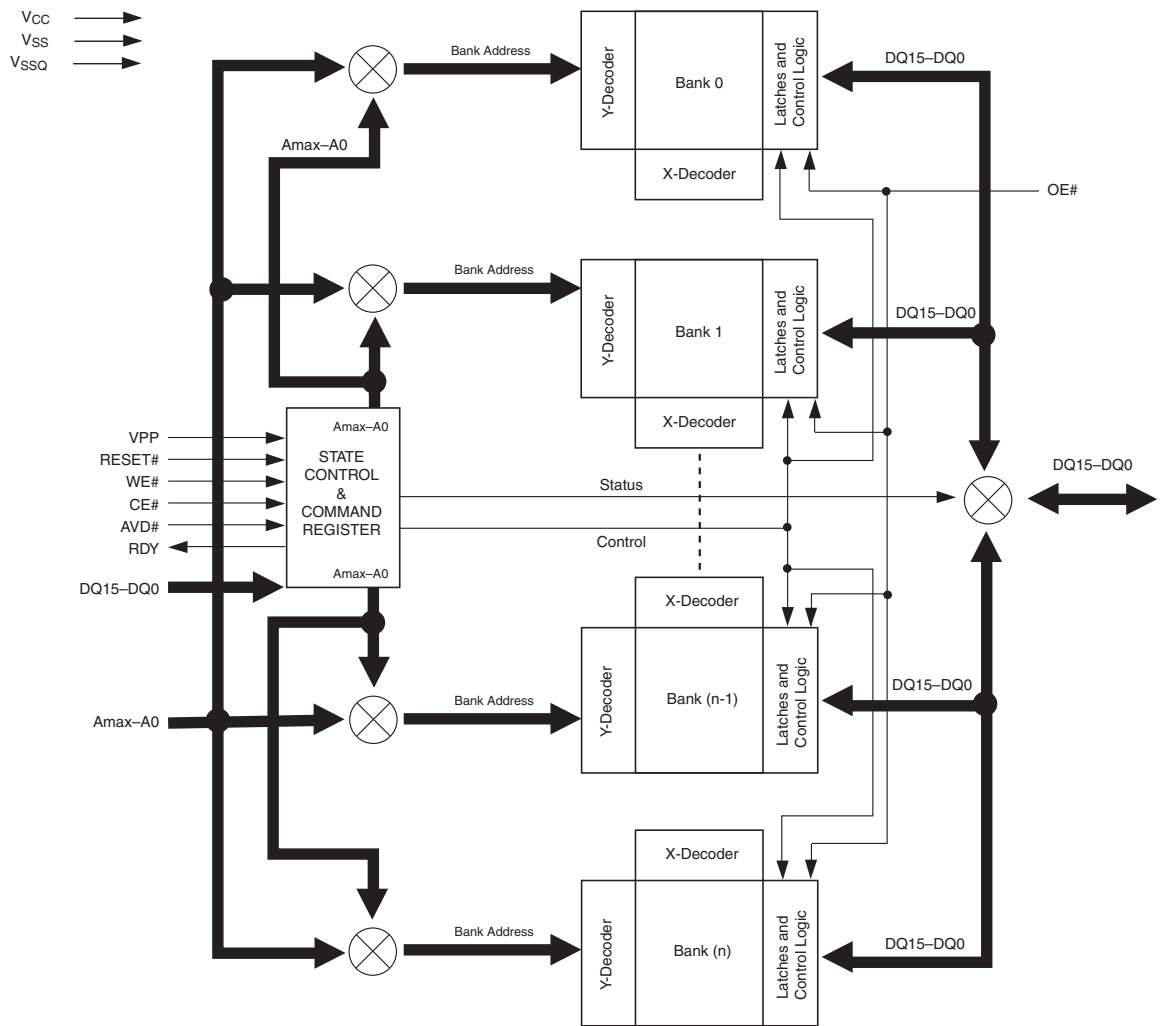
Table 2.1 identifies the input and output package connections provided on the device.

Table 2.1 Input/Output Descriptions

Symbol	Type	Description
Amax – A16		Higher order address lines. Amax = A23 for VS256R, A22 for VS128R. On the XS256R and XS128R, these inputs can be left unconnected in AADM mode.
A/DQ15 – A/DQ0	I/O	Multiplexed Address/Data input/output
CE#	Input	Flash Chip Enable. Asynchronous relative to CLK.
OE#	Input	Output Enable. Asynchronous relative to CLK for the Burst mode.
WE#	Input	Write Enable
V _{CC}	Supply	Device Power Supply
V _{CCQ}	Supply	Input/Output Power Supply (must be ramped simultaneously with V _{CC})
V _{SS}	I/O	Ground
V _{SSQ}	I/O	Input/Output Ground
NC	No Connect	No Connected internally
RDY	Output	Ready. Indicates when valid burst data is ready to be read
CLK	Input	The first rising edge of CLK in conjunction with AVD# low latches address input and activates burst mode operation. After the initial word is output, subsequent rising edges of CLK increment the internal address counter. CLK should remain low during asynchronous access
AVD#	Input	Address Valid input. Indicates to device that the valid address is present on the address inputs (address bits A15 – A0 are multiplexed, address bits Amax – A16 are address only). V _{IL} = for asynchronous mode, indicates valid address; for burst mode, cause starting address to be latched on rising edge of CLK. V _{IH} = device ignores address inputs
RESET#	Input	Hardware Reset. Low = device resets and returns to reading array data.
V _{PP}	Input	Accelerated input. At V _{IH} , accelerates programming; automatically places device in unlock bypass mode. At V _{IL} , disables all program and erase functions. Should be at V _{IH} for all other conditions.
RFU	Reserved	Reserved for future use

3. Block Diagrams

Figure 3.1 Simultaneous Operation Circuit



Notes:

1. Amax = A23 for S29VS/XS256R, A22 for S29VS/XS128R.
2. Bank(n) = 8 (S29VS/XS256/128R).

4. Physical Dimensions/Connection Diagrams

This section shows the I/O designations and package specifications for the S29VS-R.

4.1 Related Documents

The following documents contain information relating to the S29VS-R devices. Click on the title or go to www.spansion.com, or request a copy from your sales office.

- Considerations for X-ray Inspection of Surface-Mounted Flash Integrated Circuits

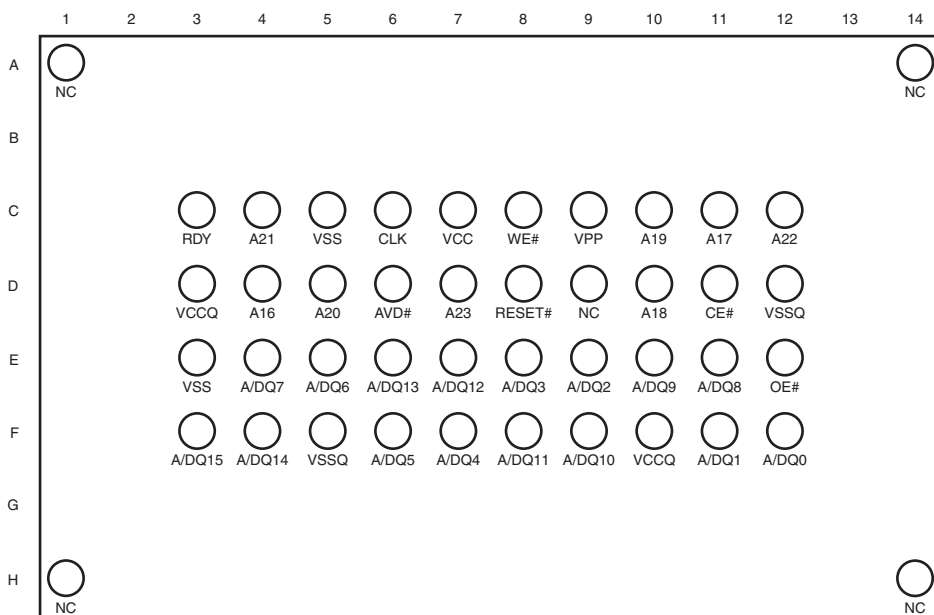
4.2 Special Handling Instructions for FBGA Package

Special handling is required for Flash Memory products in FBGA packages.

Flash memory devices in FBGA packages may be damaged if exposed to ultrasonic cleaning methods. The package and/or data integrity may be compromised if the package body is exposed to temperatures above 150°C for prolonged periods of time.

4.2.1 44-Ball Very Thin Fine-Pitch Ball Grid Array, S29VS256R/S29XS256R/S29VS128R/S29XS128R

Figure 4.1 44-Ball Very Thin Fine-Pitch Ball Grid Array, Top View, Balls Facing Down

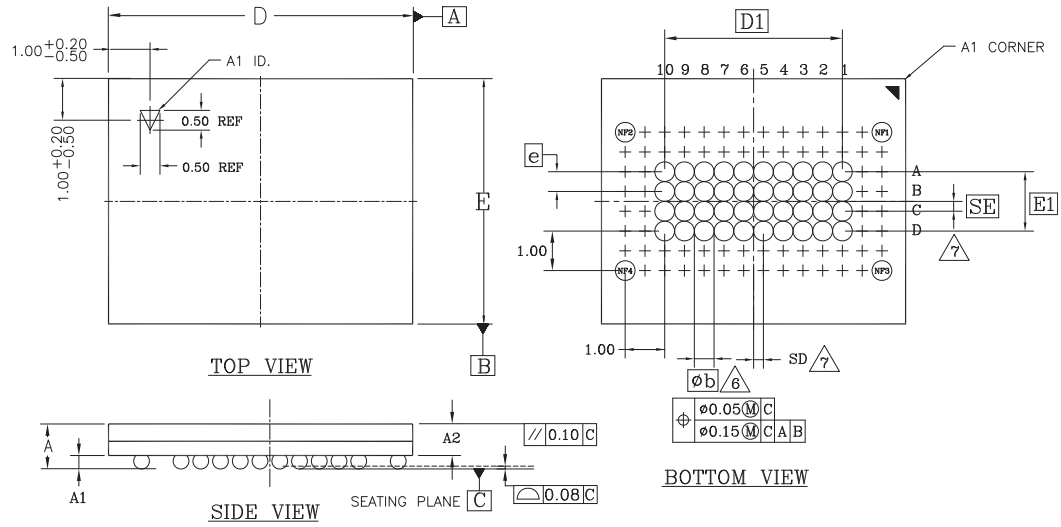


Notes:

1. Ball D7 is NC for S29VS128R.
2. Balls D7, C12, C4, D5, C10, D10, C11, D4 are NC for S29XS256R and S29XS128R

4.2.2 VDJ044-44-Ball Very Thin Fine-Pitch Ball Grid Array, 6.2mm x 7.7 mm

Figure 4.2 VDJ044—44-Ball Very Thin Fine-Pitch Ball Grid Array



PACKAGE	VDJ 044			NOTE
JEDEC	N/A			
	7.70 mm x 6.20 mm NOM PACKAGE			
SYMBOL	MIN	NOM	MAX	
A	0.86	0.93	1.00	OVERALL THICKNESS
A1	0.18	0.23	0.28	BALL HEIGHT
A2	0.64	0.71	0.78	BODY THICKNESS
[D]	7.60	7.70	7.80	BODY SIZE
[E]	6.10	6.20	6.30	BODY SIZE
[D1]	4.50 BSC.			BALL FOOTPRINT
[E1]	1.50 BSC.			BALL FOOTPRINT
MD	10			ROW MATRIX SIZE D DIRECTION
ME	4			ROW MATRIX SIZE E DIRECTION
N	44			TOTAL BALL COUNT
ø b	0.25	0.30	0.35	BALL DIAMETER
[e]	0.50 BSC.			BALL PITCH
SD / SE	0.25 BSC.			SOLDER BALL PLACEMENT
				DEPOPULATED SOLDER BALLS

NOTES:

- DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994.
- ALL DIMENSIONS ARE IN MILLIMETERS.
- BALL POSITION DESIGNATION PER JESD 95-1, SPP-010 EXCEPT AS NOTED).
- [e] REPRESENTS THE SOLDER BALL GRID PITCH.
- SYMBOL "MD" IS THE BALL ROW MATRIX SIZE IN THE "D" DIRECTION.
SYMBOL "ME" IS THE BALL COLUMN MATRIX SIZE IN THE "E" DIRECTION.
N IS THE TOTAL NUMBER OF SOLDER BALLS.
- [6] DIMENSION "b" IS MEASURED AT THE MAXIMUM BALL DIAMETER IN A PLANE PARALLEL TO DATUM C.
- [7] SD AND SE ARE MEASURED WITH RESPECT TO DATUMS A AND B AND DEFINE THE POSITION OF THE CENTER SOLDER BALL IN THE OUTER ROW.

WHEN THERE IS AN ODD NUMBER OF SOLDER BALLS IN THE OUTER ROW PARALLEL TO THE D OR E DIMENSION, RESPECTIVELY, SD OR SE = 0.000.

WHEN THERE IS AN EVEN NUMBER OF SOLDER BALLS IN THE OUTER ROW, SD OR SE = [e/2]
- NOT USED.
- "+" INDICATES THE THEORETICAL CENTER OF DEPOPULATED BALLS.
- [10] A1 CORNER TO BE IDENTIFIED BY CHAMFER, LASER OR INK MARK, METALLIZED MARK INDENTATION OR OTHER MEANS.

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5. Product Overview

The S29VS/XS-R family is 1.8-V only, simultaneous read/write, burst-mode, Flash devices. These devices have a 16 bit (word) wide data bus. All read accesses provide 16 bits of data on each bus transfer cycle. All writes take 16 bits of data from each bus transfer cycle.

Device	Mbits	Mbytes	Mwords	Banks	Mbytes / Bank
S29VS128R/S29XS128R	128	16	8	8	2
S29VS256R/S29XS256R	256	32	16	8	4

The Flash memory array is divided into banks. A bank is the address range within which one program, or erase operation may be in progress at the same time as one read operation is in progress in any other bank of the memory. This multiple bank structure enables Simultaneous Read and Write (SRW) so that code may be executed or data read from one bank while a group of data is programmed, or erased as a background task in one other bank.

Each bank is divided into sectors. A sector is the minimum address range of data which can be erased to an all Ones state. Most of the sectors are 128 KBytes each. Depending on the option ordered, either the top-4 sectors or the bottom-4 sectors are 32 KBytes each. These are called boot sectors because they are often used for holding boot code or parameters that need to be protected or erased separately from other data in the Flash array.

Programming is done via a 64 Byte write buffer. It is possible to program from one to 32 words (64 bytes) in each programming operation.

The S29VS/XS family is capable of continuous, synchronous (burst) read or linear read (8- or 16-word aligned group) with wrap around. A wrapped burst begins at the initial location and continues to the end of an 8, or 16-word aligned group then “wraps-around” to continue at the beginning of the 8, or 16-word aligned group. The burst completes with the last word before the initial location. Word wrap around burst is generally used for processor cache line fill.

6. Address Space Maps

There are five address spaces within each device:

- A Non-Volatile Flash Memory Array used for storage of data that may be randomly accessed by asynchronous or burst read operations.
- A Read Only Memory Array used for factory programmed permanent device characteristics information. This area contains the Device Identification (ID) and Common Flash Interface (CFI) information.
- A One Time Programmable (OTP) Non-volatile Flash array used for factory programmed permanent data, and customer programmable permanent data. This is called the Secure Silicon Region (SSR).
- An OTP location used to permanently protect the SSR. This is call the SSR Lock.
- A volatile register used to configure device behavior options. This is called the Configuration Register.

The main Flash Memory Array is the primary and default address space but, it may be partially overlaid by the other four address spaces with one alternate address space available at any one time. The location where the alternate address space is overlaid is defined by the address provided in the command that enables each overlay. The portion of the command address that is sufficient to select a sector is used to select the sector that is overlaid by an alternate Address Space Overlay (ASO).

Any address range, within the overlaid sector, not defined by an overlay address map, is reserved for future use. All read accesses outside of an address map within the selected sector, return non-valid data. The locations will display actively driven data but the meaning of whatever ones or zeros appear are not defined.

There are three operation modes for each bank that determine what portions of the address space are readable at any given time:

- Read Mode
- Embedded Algorithm (EA) Mode
- Address Space Overlay (ASO) Mode

Each bank of the device can be in any operation mode but, only one bank can be in EA or ASO mode at any one time.

In Read Mode, a Flash Memory Array bank may be directly read by asynchronous or burst accesses from the host system bus. The Control Unit (CU) puts all banks in Read mode during Power-on, a Hardware Reset, after a Command Reset, or after a bank is returned to Read mode from EA mode.

In EA mode the Flash memory array data in a bank is stable but undefined, and effectively unavailable for read access from the host system. While in EA mode the bank is used by the CU in the execution of commands. Typical EA mode operations are programming or erasing of data in the Flash array. All other banks are available for read access while the one bank is in EA mode. This ability to read from one bank while another bank is used in the execution of a command is called Simultaneous Read and Write (SRW) and allows for continued operation of the system via the reading of data or execution of code from other banks while one bank is programming or erasing data as a relatively long time frame background task.

In ASO mode, one of the overlay address spaces are overlaid in a bank (entered). That bank is in ASO mode and no other bank may be in EA or ASO mode. All EA activity must be completed before entering any ASO mode. A command for entering an EA or ASO mode while another bank is in EA or ASO mode will be ignored.

While an ASO mode is active (entered) in a bank, a read for Flash array data to any other bank is allowed. ASO mode selects a specific sector for the overlaid address space. Other sectors in the ASO bank still provide Flash array data and may be read during ASO mode.

The ASOs are functionally tied to the lowest address bank. The commands used to overlay (enter) these areas must select a sector address within the lowest address bank.

While SSR Lock, SSR, or Configuration Register is overlaid only the SSR Lock, SSR, or Configuration Register respectively may be programmed in the overlaid sector. While any of these ASO areas are being programmed the ASO bank switches to EA mode. The ID/CFI and factory portion of the SSR ASO is not customer programmable.

The address nomenclature used in this document is a shorthand form that shows addresses are formed from a concatenation of high order bits, sufficient to select a Sector Address (SA), with low order bits to select a location within the sector. When in Read mode and reading from the Flash Array the entire address is used to

select a specific word for asynchronous read or the starting word address of a burst read. When writing a command, the address bits between SA and the command specified least significant bits must be Zero to allow for future extension of an overlay address map.

6.1 Data Address & Quantity Nomenclature

A Bit is a single One or Zero data value. A Byte is a group of 8 bits aligned on an 8 bit boundary. A Word is a group of 16 bits aligned on a 16 bit boundary.

Throughout this document **quantities of data are generally expressed in terms of byte units**. Example: most sectors have 128 Kilo Bytes of data and is written as 128 KBytes or 128 KB. **Addresses are also expressed in byte units**. A 128 KByte sector has an address range from 00000h to 1FFFFh Byte locations. Byte units are used because most host systems and software for these systems use byte resolution addresses. Software & hardware developers most often calculate code and data sizes in terms of bytes, so this is more familiar terminology than describing data sizes in bits or words. In general, data units will not be abbreviated if possible so that full unit names of Byte, Word, or bit are used. However, there may be cases where capital B is used for byte units and lower case b is used for bit units, in situations where space is limited such as in table column headers.

In some cases data quantities will also be expressed in word or bit units in addition to the quantity shown in bytes. This may be done as an aid to readers familiar with prior device generation documentation which often provided only word or bit unit values. Word units may also be used to emphasize that, in the memory devices described in this documentation, data is always exchanged with the host system in word units. Each bus cycle transfer of read or write data on the host system bus is a transfer 16 bits of data. A read bus cycle is always a 16 bit wide transfer of data to the host system whether the host system chooses to look at all the bits or not. A write bus cycle is always a transfer of 16 bits to the memory device and the device will store all 16 bits to a register. In the case of a program operation all 16 bits of each word to be programmed will be stored in the Flash array.

Because data is always transferred in word units, the memory devices being discussed use only the address signals from the system necessary to select words. The host system byte address uses system address a0 to select bytes and a1 to select words. Flash memories with word wide data paths have traditionally started their address signal numbering with A0 being the selector for words because a byte select input is not needed. So, system address a-maximum to a1 are connected to Flash A-maximum to A0 (the documentation convention here is to use lower case for system address signal numbering and upper case for Flash address signals). In prior generation Flash documentation, address values used in commands to the flash were documented from the viewpoint of the Flash device - the bit pattern appearing on Flash address inputs A10 to A0. However, most software is written with addresses expressed in bytes. This means the address patterns shown in Flash command tables have traditionally been shifted by one bit to express them as byte address values in Flash control programs. Example: a prior generation Flash data sheet would show a command write of data value xxA0h to address 555h; this is an address pattern of 10101010101b on Flash address inputs A10 to A0; but software would define this as a byte address value of AAAh since the least significant address bit is not used by the Flash); which is 101010101010b on system address bus a11 to a0. Because system a11 to a1 is connected to Flash A10 to A0 the Flash word address of 555h and the system byte address of AAAh provides the same bit pattern on the same address inputs. Because all address values are being documented as system byte addresses, that are more familiar to software writers, the command tables have addresses that are shifted from those shown in prior generation devices.

6.2 Flash Memory Array

The Non-Volatile Flash Memory Array is organized as shown in the following tables. Devices are factory configured to have either all uniform size sectors or four smaller sectors at either the top of the device.

Table 6.1 System Versus Flash View of Address

System Address Signals	a11	a10	a9	a8	a7	a6	a5	a4	a3	a2	a1	a0
System Byte Address Hex	A				A				A			
Binary Pattern	1	0	1	0	1	0	1	0	1	0	1	0
Flash Word Address Hex	5			5				5				
Flash Address Signals	A10	A9	A8	A7	A6	A5	A4	A3	A2	A1	A0	

Table 6.2 S29VS/XS256R Sector and Memory Address Map (Top Boot)

Bank Size (Mbit)	Sector Count	Sector Size (KByte)	Bank	Sector Range	Address Range (word)	Address Range (byte)	Notes
32	224	128	0	SA000-SA031	000000h-1FFFFFFh	000000h-3FFFFFFh	Sector Starting Address – Sector Ending Address
			1	SA032-SA063	:	:	
			2	SA064-SA095	:	:	
			3	SA096-SA127	:	:	
			4	SA128-SA159	:	:	
			5	SA160-SA191	:	:	
	6	SA192-SA223	:	:			
	31	128	7	SA224-SA254	E00000h-FFFFFFFh	1C00000h-1FDFFFFFFh	
		SA255		FF0000h-FF3FFFh	1FE0000h-1FE7FFFh		
	4	32		SA256	FF4000h-FF7FFFh	1FE8000h-1FEFFFFh	
				SA257	FF8000h-FFBFFFh	1FF0000h-1FF7FFFh	
			SA258	FFC000h-FFFFFFh	1FF8000h-1FFFFFFh		

Note:

All tables have been condensed to show sector-related information for an entire device on a single page. Sectors and their address ranges that are not explicitly listed (such as SA008-SA009) have sector starting and ending addresses that form the same pattern as all other sectors of that size. For example, all 128 KB sectors have the byte address pattern x000000h-x1FFFFFFh.

Table 6.3 S29VS/XS256R Sector and Memory Address Map (Bottom Boot)

Bank Size (Mbit)	Sector Count	Sector Size (Kbyte)	Bank	Sector Range	Address Range (word)	Address Range (byte)	Notes		
32	4	32	0	SA000	000000h-003FFFh	000000h-007FFFh	Sector Starting Address – Sector Ending Address		
				SA001	004000h-007FFFh	008000h-00FFFFh			
				SA002	008000h-00BFFFh	010000h-017FFFh			
				SA003	00C000h-00FFFFh	018000h-01FFFFh			
	31	128		SA004-SA034	010000h-1FFFFFFh	020000h-3FFFFFFh			
	224	128			1	SA035-SA066		:	:
					2	SA067-SA098		:	:
					3	SA099-SA130		:	:
					4	SA131-SA162		:	:
					5	SA163-SA194		:	:
					6	SA195-SA226		:	:
					7	SA227-SA258		E00000h-FFFFFFh	1C00000h-1FFFFFFh

Note:

All tables have been condensed to show sector-related information for an entire device on a single page. Sectors and their address ranges that are not explicitly listed (such as SA008-SA009) have sector starting and ending addresses that form the same pattern as all other sectors of that size. For example, all 128 KB sectors have the byte address pattern x000000h-x1FFFFFFh.

Table 6.4 S29VS/XS128R Sector and Memory Address Map (Top Boot)

Bank Size (Mbit)	Sector Count	Sector Size (KByte)	Bank	Sector Range	Address Range (word)	Address Range (byte)	Notes
16	112	128	0	SA000-SA015	000000h-0FFFFFFh	000000h-1FFFFFFh	Sector Starting Address – Sector Ending Address
			1	SA016-SA031	:	:	
			2	SA032-SA047	:	:	
			3	SA048-SA063	:	:	
			4	SA064-SA079	:	:	
			5	SA080-SA095	:	:	
			6	SA096-SA111	:	:	
	15	128	7	SA112-SA126	700000h-7EFFFFh	E00000h-FDFFFFh	
	4	32		SA127	7F0000h-7F3FFFh	FE0000h-FE7FFFh	
				SA128	7F4000h-7F7FFFh	FE8000h-FEFFFFh	
				SA129	7F8000h-7FBFFFh	FF0000h-FF7FFFh	
				SA130	7FC000h-7FFFFFFh	FF8000h-FFFFFFh	

Note:

All tables have been condensed to show sector-related information for an entire device on a single page. Sectors and their address ranges that are not explicitly listed (such as SA008-SA009) have sector starting and ending addresses that form the same pattern as all other sectors of that size. For example, all 128 KB sectors have the byte address pattern x000000h-x1FFFFFFh.

Table 6.5 S29VS/XS128R Sector and Memory Address Map (Bottom Boot)

Bank Size (Mbit)	Sector Count	Sector Size (Kbyte)	Bank	Sector Range	Address Range (word)	Address Range (byte)	Notes
16	4	32	0	SA000	000000h-003FFFh	000000h-007FFFh	Sector Starting Address – Sector Ending Address
				SA001	004000h-007FFFh	008000h-00FFFFh	
				SA002	008000h-00BFFFh	010000h-017FFFh	
				SA003	00C000h-00FFFFh	018000h-01FFFFh	
				SA004-SA018	010000h-0FFFFFFh	020000h-1FFFFFFh	
	112	128	1	SA019-SA034	:	:	
			2	SA035-SA050	:	:	
			3	SA051-SA066	:	:	
			4	SA067-SA082	:	:	
			5	SA083-SA098	:	:	
			6	SA099-SA114	:	:	
			7	SA115-SA130	700000h-7FFFFFFh	E00000h-FFFFFFh	

Note:

All tables have been condensed to show sector-related information for an entire device on a single page. Sectors and their address ranges that are not explicitly listed (such as SA008-SA009) have sector starting and ending addresses that form the same pattern as all other sectors of that size. For example, all 128 KB sectors have the byte address pattern x000000h-x1FFFFFFh.

6.3 Address/Data Interface

There are two options for connection to the address and data buses.

- Address and Data Multiplexed (ADM) mode. On the S29VS-R devices, the upper address is supplied on separate signal inputs and the lower 16-bits of address are multiplexed with 16-bit data on the A/DQ15 to A/DQ0 I/Os.
- Address-high, Address-low, and Data Multiplexed (AADM) mode. On the S29XS-R devices, the upper and lower address are multiplexed with 16-bit data on the A/DQ15 to A/D0 signal I/Os.

The two options allow use with the traditional address/data multiplexed NOR interface (S29NS family), or an address multiplexed/data multiplexed interface with the lowest signal count.

6.3.1 ADM Interface (S29VS256R and S29VS128R)

A number of processors use ADM interface as a way to reduce pin count. The system permanently connects the upper address bits (A[MAX:16]) to the device. When AVD# is LOW it connects A[15:0] to DQ[15:0]. The address is latched on the rising edge of AVD#. When AVD# is HIGH, the system connects the data bus to DQ[15:0]. This results in 16-pin savings from the traditional Address and Data in Parallel (ADP) interface.

6.3.2 AADM Interface (S29XS256R and S29XS128R)

Signal input and output (I/O) connections on a high complexity component such as an Application Specific Integrated Circuit (ASIC) are a limited resource. Reducing signal count on any interface of the ASIC allows for either more features or lower package cost. The memory interface described in this section is intended to reduce the I/O signal count associated with the Flash memory interface with an ASIC.

The interface is called Address-High, Address-Low, and Data Multiplexed (AADM) because all address and data information is time multiplexed on a single 16-bit wide bus. This interface is electrically compatible with existing ADM 16-bit wide random access static memory interfaces but uses fewer address signals. In that sense AADM is a signal count subset of existing static memory interfaces. This interface can be implemented in existing memory controller designs, as an additional mode, with minimal changes. No new I/O technology is needed and existing memory interfaces can continue to be supported while the electronics industry adopts this new interface. ASIC designers can reuse the existing memory address signals above A15 for other functions when an AADM memory is in use.

By breaking up the memory address in to two time slots the address is naturally extended to be a 32-bit word address. But, using two bus cycles to transfer the address increases initial access latency by increasing the time address is using the bus. However, many memory accesses are to locations in memory nearby the previous access. Very often it is not necessary to provide both cycles of address. This interface stores the high half of address in the memory so that if the high half of address does not change from the previous access, only the low half of address needs to be sent on the bus. If a new upper address is not captured at the beginning of an access the last captured value of the upper address is used. This allows accesses within the same 128-KByte address range to provide only the lower address as part of each access.

In AADM mode two signal rising edges are needed to capture the upper and lower address portions in asynchronous mode or two signal combinations over two clocks is needed in synchronous mode. In asynchronous mode the upper address is captured by an AVD# rising edge when OE# is Low; the lower address is captured on the rising edge of AVD# with OE# High. In synchronous mode the upper address is captured at the rising clock edge when AVD# and OE# are Low; the lower address is captured at the rising edge of clock when AVD# is Low and OE# is High.

CE# going High at any time during the access or OE# returning High after RDY is first asserted High during an access, terminates the read access and causes the address/data bus direction to switch back to input mode. The address/data bus direction switches from input to output mode only after an Address-Low capture when AVD# is Low and OE# is High. This prevents the assertion of OE# during Address-High capture from causing a bus conflict between the host address and memory data signals. Note, in burst mode, this implies at least one cycle of CE# or OE# High before an Address-high for a new access may be placed on the bus so that there is time for the memory to recognize the end of the previous access, stop driving data outputs, and ignore OE# so that assertion of OE# with the new Address-high does not create a bus conflict with a new address being driven on the bus. At high bus frequencies more than one cycle may be need in order to allow time for data outputs to stop driving and new address to be driven (bus turn around time).

During a write access, the address/data bus direction is always in the input mode.

The upper address is set to Zero or all Ones, for bottom or top boot respectively, during a Hardware Reset, operate in ADM mode during the early phase of boot code execution where only a single address cycle would be issued with the lower 16 bit of the address reaching the memory in AADM mode. The default high order address bits will direct the early boot accesses to the 128 Kbytes at the boot end of the device. Note that in AADM interface mode this effectively requires that one of the boot sectors is selected for any address overlay mode because in the initial phase of AADM mode operation the host memory controller may only issue the low order address thus limiting the early boot time address space to the 128 Kbytes at the boot end of the device.










6.3.3 Default Access Mode


Upon power-up or hardware reset, the device defaults to the Asynchronous Access mode.

6.4 Bus Operations

Table 6.6 describes the required state of each input signal for each bus operation.

Table 6.6 Device Bus Operations

Operation	CE#	OE#	WE#	CLK	AVD#	A28-A16	A/DQ 15-A/DQ0	RESET#
Standby & Reset								
Standby (CE# deselect)	H	X	X	X	X	X	High-Z	H
Hardware Reset	X	X	X	X	X	X	High-Z	L
Asynchronous Mode Operations								
Asynchronous Address Latch (S29VS256R and S29VS128R)	L	H	X	X		Addr In	Addr In	H
Asynchronous Upper Address Latch (S29XS256R and S29XS128R Only)	L	L	H	X		X	Addr In	H
Asynchronous Lower Address Latch (S29XS256R and S29XS128R Only)	L	H	X	X		X	Addr In	H
Asynchronous Read	L	L	H	X	H	X	Data Output Valid	H
Asynchronous Write Latched Data	L	H		X	H	X	Data Input Valid	H
Synchronous Mode Operations								
Latch Starting Burst Address by CLK - ADM mode	L	H	H		L	Addr In	Addr In	H
Latch Upper Starting Burst Address by CLK (S29XS256R and S29XS128R Only)	L	L	H		L	X	Addr In	H
Latch Lower Starting Burst Address by CLK (S29XS256R and S29XS128R Only)	L	H	H		L	X	Addr In	H
Burst Read and advance to next address (1)	L	L	H		H	X	Data Output Valid	H
Terminate current Burst cycle		X	X	X	X	X	High-Z	H

Legend:
L = Logic 0, H = Logic 1, X = can be either V_{IL} or V_{IH} .  = rising edge.

Note:
1. Data is delivered by a read operation only after the burst initial wait state count has been satisfied.

6.5 Device ID and CFI (ID-CFI)

There are two traditional methods for systems to identify the type of Flash memory installed in the system. One has been traditionally been called Autoselect and is now referred to as Device Identification (ID). A command is used to enable an address space overlay where up to 16 word locations can be read to get JEDEC manufacturer identification (ID), device ID, and some configuration and protection status information from the Flash memory. The system can use the manufacturer and device IDs to select the appropriate driver software to use with the Flash device. The other method is called Common Flash Interface (CFI). It also uses a command to enable an address space overlay where an extendable table of standard information about how the Flash memory is organized and behaves can be read. With this method the driver software does not have to be written with the specifics of each possible memory device in mind. Instead the driver software is written in a more general way to handle many different devices but adjusts the driver behavior based on the information in the CFI table stored in the Flash memory. Traditionally these two address spaces have used separate commands and were separate overlays. However, the mapping of these two address spaces are non-overlapping and so can be combined in to a single address space and appear together in a single overlay. Either of the traditional commands used to access (enter) the Autoselect (ID) or CFI overlay will cause the now combined ID-CFI address map to appear.

A write at any sector address, in bank zero, having the least significant byte address value of AAh, with xx98h or xx90h data, switches the addressed sector to an overlay of the ID-CFI address map. These are called ID-CFI Enter commands and are only valid when written to the specified bank when it is in read mode. The ID-CFI address map appears within, and replaces Flash Array data of, the selected sector address range. The ID-CFI enter commands use the same address and data values used on previous generation memories to access the JEDEC Manufacturer ID (Autoselect) and Common Flash Interface (CFI) information, respectively. While the ID-CFI address space is overlaid, any write with xxF0h data to the device will remove the overlay and return the selected sector to showing Flash memory array data. Thus, the ID-CFI address space and commands are backward compatible with standard memory discovery algorithms.

Within the ID-CFI address map there are two subsections:

Table 6.7 ID-CFI Address Map Overview

Byte Address	Description	Size Allocated (Bytes)	Read/Write
(SA) + 00000h to 0001Fh	JEDEC ID (traditional Autoselect values)	32	Read Only
(SA) + 00020h to CEh h	CFI data structure	174	Read Only

For the complete address map see Tables in [Section 11.2, Device ID and Common Flash Memory Interface Address Map](#) on page 58.

6.5.1 JEDEC Device ID

The Joint Electron Device Engineering Council (JEDEC) standard JEP106T defines a method for reading the manufacturer ID and device ID of a compliant memory. This information is primarily intended for programming equipment to automatically match a device with the corresponding programming algorithm.

The JEDEC ID information is structured to work with any memory data bus width e.g. x8, x16, x32. The code values are always byte wide but are located at bus width address boundaries such that incrementing the device address inputs will read successive byte, word, or double word locations with the codes always located in the least significant byte location of the data bus. Because the data bus is word wide each code byte is located in the lower half of each word location and the high order byte is always zero.

6.5.2 Common Flash Memory Interface

The Common Flash Interface (CFI) specification defines a standardized data structure that may be read from a flash memory device, which allows vendor-specified software algorithms to be used for entire families of devices. The data structure contains information for system configuration such as various electrical and timing parameters, and special functions supported by the device. Software support can then be device-independent, JEDEC ID-independent, and forward-and-backward-compatible for the specified flash device families.

The system can read CFI information at the addresses within the selected sector as shown in [Section 11.2, Device ID and Common Flash Memory Interface Address Map](#) on page 58.

Like the JEDEC Device ID information, CFI information is structured to work with any memory data bus width e.g. x8, x16, x32. The code values are always byte wide but are located at data bus width address boundaries such that incrementing the device address reads successive byte, word, or double word locations with the codes always located in the least significant byte location of the data bus. Because the data bus is word wide each code byte is located in the lower half of each word location and the high order byte is always zero.

For further information, please refer to the Spansion CFI Version 1.4 (or later) Specification and the Spansion CFI Publication 100 (see also JEDEC publications JEP137-A and JESD68.01). Please contact JEDEC (<http://www.jedec.org>) for their standards and the Spansion CFI Publications may be found at the Spansion Web site (http://www.spansion.com/Support/AppNotes/CFI_v1.4_VendorSpec_Ext_A1.pdf at the time of this document's publication).

6.5.3 Secured Silicon Region

The Secured Silicon region provides an extra Flash memory area that can be programmed once and permanently protected from further changes. The Secured Silicon Region is 512 bytes in length. It consists of 256 bytes for factory data and 256 bytes for customer-secured data.

The Secured Silicon Region (SSR) is overlaid in the sector address specified by the SSR enter command.

Table 6.8 Secured Silicon Region

Byte Address Range	Secure Silicon Region	Size
(SA) + 0000h to 00FFh	Factory	256 Bytes
(SA) + 0100h to 01FFh	Customer	256 Bytes

6.5.4 Configuration Register

The Configuration Register Enter command is only valid when written to a bank that is in Read mode. The configuration register mode address map appears within, and replaces Flash Array data of, the selected sector address range. The meaning of the configuration register bits is defined in the configuration register operation description. In configuration register mode, a write of 00F0h to any address will return the sector to Read mode.

7. Device Operations

This section describes the read and write bus operations, program, erase, simultaneous read/write, handshaking, and reset features of the Flash devices.

The address space of the Flash Memory Array is divided into banks. There are three operation modes for each bank:

- Read Mode
- Embedded Algorithm (EA) Mode
- Address Space Overlay (ASO) Mode

Each bank of the device can be in any operation mode but, only one bank can be in EA or ASO mode at any one time.

In Read Mode a Flash Memory Array bank may be read by simply selecting the memory, supplying the address, and taking read data when it is ready. This is done by asynchronous or burst accesses from the host system bus. The CU puts all banks in Read mode during Power-on, a Hardware Reset, after a Command Reset, or after a bank is returned to Read mode from EA mode.

During a burst read access valid read data is indicated by the RDY signal being High. When RDY is Low burst read data is not valid and wait states must be added. The use of the RDY signal to indicate when valid data is transferred on the system data bus is called handshaking or flow control.

EA and ASO modes are initiated by writing specific address and data patterns into command registers (see [Table 11.1 on page 56](#)). The command registers do not occupy any memory locations; they are loaded by write bus cycles with the address and data information needed to execute a command. The contents of the registers serve as input to the Control Unit (CU) and the CU dictates the function of the device. Writing incorrect address and data values or writing them in an improper sequence may place the device in an unknown state, in which case the system must write the reset command to return all banks to Read mode.

The Flash memory array data in a bank that is in EA mode, is stable but undefined, and effectively unavailable for read access from the host system. While in EA mode the bank is used by the CU in the execution of commands. Typical command operations are programming or erasing of data in the Flash array. All other banks are available for read access while the one bank is in EA mode. This ability to read from one bank while another bank is used in the execution of a command is called Simultaneous Read and Write (SRW) and allows for continued operation of the system via the reading of data or code from other banks while one bank is programming or erasing data as a relatively long time frame background task. Only a status register read command can be used in a bank in EA mode to retrieve the EA status.

While any one of the overlay address spaces are overlaid in a bank (entered) that bank is in ASO mode and no other bank may be in EA or ASO mode. All EA activity must be completed or suspended before entering any ASO mode. A command for entering an EA or ASO mode while another bank is in EA or ASO mode will be ignored.

While an ASO mode is active (entered) in a bank, a read for Flash array data to any other bank is allowed. ASO mode selects a specific sector for the overlaid address space. Other sectors in the ASO bank still provide Flash array data and may be read during ASO mode.

While SSR Lock, SSR, or Configuration Register is overlaid only the SSR Lock, SSR, or Configuration Register respectively may be programmed in the overlaid sector. While any of these ASO areas are being programmed the ASO bank switches to EA mode. The ID/CFI and factory portion of the SSR ASO is not customer programmable. An attempt to program in these areas will fail.

7.1 Asynchronous Read

The device defaults to reading array data asynchronously after device power-up or hardware reset. The device is in the Asynchronous mode when Bit 15 of the Configuration register is set to '1'. To read data from the memory array, the system must first assert CE# and AVD# to V_{IL} with WE# at V_{IH} and a valid address.

Address access time (t_{ACC}) is equal to the delay from stable addresses to valid output data. The chip enable access time (t_{CE}) is the delay from stable CE# to valid data at the outputs. See [10.9.2, AC Characteristics–Asynchronous Read on page 49](#). Any input on CLK is ignored while in Asynchronous mode.

7.1.1 S29VS-R ADM Access

With CE# at V_{IL} , WE# at V_{IH} , and OE# at V_{IH} , the system presents the address to the device and drives AVD# to V_{IL} . AVD# is kept at V_{IL} for at least t_{AVDP} ns. The address is latched on the rising edge of AVD#.

7.1.2 S29XS-R AADM Access

With CE# at V_{IL} , WE# at V_{IH} , and OE# at V_{IL} , the system presents the upper address bits to DQ and drives AVD# to V_{IL} . The upper address bits are latched when AVD# transitions to V_{IH} . The system then drives AVD# to V_{IL} again, with OE# at V_{IH} and the lower address bits on the DQ signals. The lower address bits are latched on the next rising edge of AVD#.

7.2 Synchronous (Burst) Read Mode and Configuration Register

The device is capable of continuous sequential burst operation and linear burst operation of a preset length.

In order to use Synchronous (Burst) Read Mode the configuration register bit 15 must be set to 0.

Prior to entering burst mode, the system should determine how many wait states are needed for the initial word of each burst access (see table below), what mode of burst operation is desired, how the RDY signal transitions with valid data, and output drive strength. The system would then write the configuration register command sequence. See [Configuration Register on page 26](#) for further details.

When the appropriate number of Wait States have occurred, data is output after the **rising edge** of the CLK. Subsequent words are output t_{BACC} after the rising edge of each successive clock cycle, which automatically increments the internal address counter. RDY indicates the initial latency and any subsequent waits.

7.2.1 S29VS-R ADM Access

To burst read data from the memory array in ADM mode, the system must assert CE# to V_{IL} , and provide a valid address while driving AVD# to V_{IL} for one cycle. OE# must remain at V_{IH} during the one cycle that AVD# is at V_{IL} . The data appears on A/DQ15 -A/DQ0 when CE# remains at V_{IL} , after OE# is driven to V_{IL} and the synchronous access times are satisfied. The next data in the burst sequence is read on each clock cycle that OE# and CE# remain at V_{IL} .

OE# does not terminate a burst access if it rises to V_{IH} during a burst access. The outputs will go to high impedance but the burst access will continue until terminated by CE# going to V_{IH} , or AVD# returns to V_{IL} with a new address to initiate a another burst access.

7.2.2 S29XS-R AADM Access

To burst read data from the memory array in AADM mode, the system must assert CE# to V_{IL} , OE# must be driven to V_{IL} with AVD# for one cycle while the upper address is valid. The rising edge of CLK when OE# and AVD# are at V_{IL} captures the upper 16 bits of address. The rising edge of CLK when OE# is at V_{IH} and AVD# is at V_{IL} latches the lower 16 bits of address. The data appears on A/DQ15 -A/DQ0 when CE# remains at V_{IL} , after OE# is driven to V_{IL} and the synchronous access times are satisfied. The next data in the burst sequence is read on each clock cycle that OE# and CE# remain at V_{IL} .

Once OE# returns to V_{IH} during a burst read the OE# no longer enables the outputs until after AVD# is at V_{IL} with OE# at V_{IH} - which signals that address-low has been captured for the next burst access. This is so that OE# at V_{IL} may be used in conjunction with AVD# at V_{IL} to indicate address-high on the A/DQ signals without enabling the A/DQ outputs, thus avoiding data output contention with Address-high.

The device has a fixed internal address boundary that occurs every 256 Bytes (128 words). A boundary crossing latency of one or two additional wait states may be required. The device also reads data in 16 byte (8 word) aligned and length groups. When the initial address is not aligned at the beginning of a 16 byte boundary, additional wait states may be needed when crossing the first 16 byte boundary. The number of additional wait states depends on the clock frequency and starting address location.

The following Tables show the latency for initial and boundary crossing wait state operation (note that ws = wait state).

Table 7.1 Initial Wait State vs. Frequency

Wait State	Frequency (Maximum MHz)
3	27
4	40
5	54
6	66
7	80
8	95
9	104
10	120

Note:

The default initial wait state delay after power on or reset is 13 wait states.

Table 7.2 Address Latency for 10 -13 Wait States

Word	Initial Wait	Subsequent Clock Cycles After Initial Wait States									
0	10 -13 wait states	D0	D1	D2	D3	D4	D5	D6	D7	+2 ws (1)	D8
1		D1	D2	D3	D4	D5	D6	D7	1 ws	+2 ws	D8
2		D2	D3	D4	D5	D6	D7	1 ws	1 ws	+2 ws	D8
3		D3	D4	D5	D6	D7	1 ws	1 ws	1 ws	+2 ws	D8
4		D4	D5	D6	D7	1 ws	1 ws	1 ws	1 ws	+2 ws	D8
5		D5	D6	D7	1 ws	1 ws	1 ws	1 ws	1 ws	+2 ws	D8
6		D6	D7	1 ws	1 ws	1 ws	1 ws	1 ws	1 ws	+2 ws	D8
7		D7	1 ws	1 ws	1 ws	1 ws	1 ws	1 ws	1 ws	+2 ws	D8

Note:

1. This column applies to the 256 Byte boundary only.

Table 7.3 Address Latency for 9 Wait States

Word	Initial Wait	Subsequent Clock Cycles After Initial Wait States									
0	9 wait states	D0	D1	D2	D3	D4	D5	D6	D7	+1 ws (1)	D8
1		D1	D2	D3	D4	D5	D6	D7	1 ws	+1 ws	D8
2		D2	D3	D4	D5	D6	D7	1 ws	1 ws	+1 ws	D8
3		D3	D4	D5	D6	D7	1 ws	1 ws	1 ws	+1 ws	D8
4		D4	D5	D6	D7	1 ws	1 ws	1 ws	1 ws	+1 ws	D8
5		D5	D6	D7	1 ws	1 ws	1 ws	1 ws	1 ws	+1 ws	D8
6		D6	D7	1 ws	1 ws	1 ws	1 ws	1 ws	1 ws	+1 ws	D8
7		D7	1 ws	1 ws	1 ws	1 ws	1 ws	1 ws	1 ws	+1 ws	D8

Note:

1. This column applies to the 256 Byte boundary only.

Table 7.4 Address Latency for 8 Wait States

Word	Initial Wait	Subsequent Clock Cycles After Initial Wait States								
		D0	D1	D2	D3	D4	D5	D6	D7	D8
0	8 wait states	D0	D1	D2	D3	D4	D5	D6	D7	D8
1		D1	D2	D3	D4	D5	D6	D7	1 ws	D8
2		D2	D3	D4	D5	D6	D7	1 ws	1 ws	D8
3		D3	D4	D5	D6	D7	1 ws	1 ws	1 ws	D8
4		D4	D5	D6	D7	1 ws	1 ws	1 ws	1 ws	D8
5		D5	D6	D7	1 ws	1 ws	1 ws	1 ws	1 ws	D8
6		D6	D7	1 ws	1 ws	1 ws	1 ws	1 ws	1 ws	D8
7		D7	1 ws	1 ws	1 ws	1 ws	1 ws	1 ws	1 ws	D8

Table 7.5 Address Latency for 7 Wait States

Word	Initial Wait	Subsequent Clock Cycles After Initial Wait States								
		D0	D1	D2	D3	D4	D5	D6	D7	D8
0	7 wait states	D0	D1	D2	D3	D4	D5	D6	D7	D8
1		D1	D2	D3	D4	D5	D6	D7	D8	D9
2		D2	D3	D4	D5	D6	D7	1 ws	D8	D9
3		D3	D4	D5	D6	D7	1 ws	1 ws	D8	D9
4		D4	D5	D6	D7	1 ws	1 ws	1 ws	D8	D9
5		D5	D6	D7	1 ws	1 ws	1 ws	1 ws	D8	D9
6		D6	D7	1 ws	1 ws	1 ws	1 ws	1 ws	D8	D9
7		D7	1 ws	1 ws	1 ws	1 ws	1 ws	1 ws	D8	D9

Table 7.6 Address Latency for 6 Wait States

Word	Initial Wait	Subsequent Clock Cycles After Initial Wait States								
		D0	D1	D2	D3	D4	D5	D6	D7	D8
0	6 wait states	D0	D1	D2	D3	D4	D5	D6	D7	D8
1		D1	D2	D3	D4	D5	D6	D7	D8	D9
2		D2	D3	D4	D5	D6	D7	D8	D9	D10
3		D3	D4	D5	D6	D7	1 ws	D8	D9	D10
4		D4	D5	D6	D7	1 ws	1 ws	D8	D9	D10
5		D5	D6	D7	1 ws	1 ws	1 ws	D8	D9	D10
6		D6	D7	1 ws	1 ws	1 ws	1 ws	D8	D9	D10
7		D7	1 ws	1 ws	1 ws	1 ws	1 ws	D8	D9	D10

Table 7.7 Address Latency for 5 Wait States

Word	Initial Wait	Subsequent Clock Cycles After Initial Wait States								
		D0	D1	D2	D3	D4	D5	D6	D7	D8
0	5 wait states	D0	D1	D2	D3	D4	D5	D6	D7	D8
1		D1	D2	D3	D4	D5	D6	D7	D8	D9
2		D2	D3	D4	D5	D6	D7	D8	D9	D10
3		D3	D4	D5	D6	D7	D8	D9	D10	D11
4		D4	D5	D6	D7	1 ws	D8	D9	D10	D11
5		D5	D6	D7	1 ws	1 ws	D8	D9	D10	D11
6		D6	D7	1 ws	1 ws	1 ws	D8	D9	D10	D11
7		D7	1 ws	1 ws	1 ws	1 ws	D8	D9	D10	D11

Table 7.8 Address Latency for 4 Wait States

Word	Initial Wait	Subsequent Clock Cycles After Initial Wait States								
		D0	D1	D2	D3	D4	D5	D6	D7	D8
0	4 wait states	D0	D1	D2	D3	D4	D5	D6	D7	D8
1		D1	D2	D3	D4	D5	D6	D7	D8	D9
2		D2	D3	D4	D5	D6	D7	D8	D9	D10
3		D3	D4	D5	D6	D7	D8	D9	D10	D11
4		D4	D5	D6	D7	D8	D9	D10	D11	D12
5		D5	D6	D7	1 ws	D8	D9	D10	D11	D12
6		D6	D7	1 ws	1 ws	D8	D9	D10	D11	D12
7		D7	1 ws	1 ws	1 ws	D8	D9	D10	D11	D12

Table 7.9 Address Latency for 3 Wait States

Word	Initial Wait	Subsequent Clock Cycles After Initial Wait States								
		D0	D1	D2	D3	D4	D5	D6	D7	D8
0	3 wait states	D0	D1	D2	D3	D4	D5	D6	D7	D8
1		D1	D2	D3	D4	D5	D6	D7	D8	D9
2		D2	D3	D4	D5	D6	D7	D8	D9	D10
3		D3	D4	D5	D6	D7	D8	D9	D10	D11
4		D4	D5	D6	D7	D8	D9	D10	D11	D12
5		D5	D6	D7	D8	D9	D10	D11	D12	D13
6		D6	D7	1 ws	D8	D9	D10	D11	D12	D13
7		D7	1 ws	1 ws	D8	D9	D10	D11	D12	D13

7.2.3 Continuous Burst

The device continues to output sequential burst data from the memory array, wrapping around to address 0000000h after it reaches the highest addressable memory location, until the system drives CE# high, RESET# low, or AVD# low in conjunction with a new address. See [Table 6.6, Device Bus Operations](#) on page 18.

If the host system crosses a bank boundary while reading in burst mode, and the subsequent bank is not programming or erasing, an address boundary crossing latency might be required. If the host system crosses the bank boundary while the subsequent bank is programming or erasing, continuous burst halts (RDY will be disabled and data will continue to be driven).

7.2.4 8-, 16-Word Linear Burst with Wrap Around

Table 7.10 Burst Address Groups

Mode	Group Size	Group Byte Address Ranges
8-word	16 bytes	0-Fh, 10-1Fh, 20-2Fh,...
16-word	32 bytes	0-1Fh, 20-3Fh, 30-4Fh,...

The remaining two modes are fixed length linear burst with wrap around, in which a fixed number of words are read from consecutive addresses. In each of these modes, the burst addresses read are determined by the group within which the starting address falls. The groups are sized according to the number of words read in a single burst sequence for a given mode (see [Table 7.10](#)).

As an example: if the starting address in the 8-word mode is system byte address 3Ch, the address range to be read would be byte address 30-3Fh, and the burst sequence would be 3C-3E-30-32-34-36-38-3Ah. The burst sequence begins with the starting address written to the device, wraps back to the first address in the selected group, and outputs a maximum of 8 words. No additional wait states will be required within the 8-word burst. The 8th word will continue to be driven until the burst operation is aborted (CE# goes to V_{IH}, a new address is latched in for a new burst operation, or a hardware reset). In a similar fashion, the 16-word Linear Wrap modes begin their burst sequence on the starting address written to the device, and then wrap back to the first address in the selected address group. Additional wait states could be added the first time the